

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination TAKEI ET AL.	
		Examiner Chuong A. Luu	Art Unit 2818	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,158,828	10-1992	Sudani et al.	428/368
	B	US-			
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	D	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP2002-100562	05-2002	Japan	Takano et al.	
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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